TOSHIBA Field Effect Transistor Silicon N-Channel MOS Type (High-speed U-MOS III)

TPC8013-H

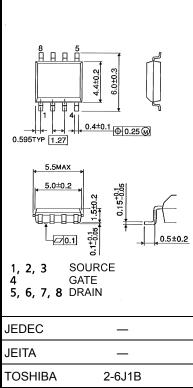
High-Efficiency DC/DC Converter Applications Notebook PC Applications Portable-Equipment Applications

- Small footprint due to a small and thin package
- High-speed switching
- Small gate charge: QSW = 15.6 nc (typ.)
- Low drain-source ON-resistance: RDS (ON) = $5.4 \text{ m}\Omega$ (typ.)
- High forward transfer admittance: $|Y_{fs}| = 25 \text{ S (typ.)}$
- Low leakage current: $I_{DSS} = 10 \mu A (max) (V_{DS} = 30 V)$
- Enhancement mode: $V_{th} = 1.1$ to 2.3 V ($V_{DS} = 10$ V, $I_{D} = 1$ mA)

Absolute Maximum Ratings (Ta = 25°C)

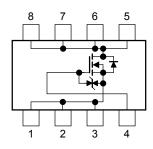
| Characte | eristic | Symbol | Rating | Unit | |
|-----------------------|---------------------------------|------------------|------------|------|--|
| Drain-source voltage | | V_{DSS} | 30 | V | |
| Drain-gate voltage (R | $k_{GS} = 20 \text{ k}\Omega$) | V_{DGR} | 30 | V | |
| Gate-source voltage | _ | V_{GSS} | ±20 | V | |
| Drain current | DC (Note 1) | ΙD | 15 | Α | |
| Diam current | Pulse (Note 1) | I_{DP} | 60 | | |
| Drain power dissipati | on $(t = 10 s)$ (Note 2a) | P_{D} | 1.9 | W | |
| Drain power dissipati | on (t = 10 s) (Note 2b) | P_{D} | 1.0 | W | |
| Single-pulse avalance | ne energy (Note 3) | E _{AS} | 146 | mJ | |
| Avalanche current | | I _{AR} | 15 | Α | |
| Repetitive avalanche | energy Note 2a) (Note 4) | E _{AR} | 0.19 | mJ | |
| Channel temperature | | T _{ch} | 150 | °C | |
| Storage temperature | range | T _{stg} | -55 to 150 | °C | |

Unit: mm



Weight: 0.085 g (typ.)

Circuit Configuration



Note: For Notes 1 to 4, refer to the next page.

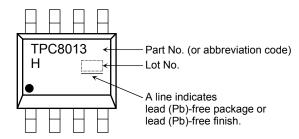
Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

This transistor is an electrostatic-sensitive device. Handle with care.

Thermal Characteristics

| Characteristic | Symbol | Max | Unit |
|--|------------------------|------|------|
| Thermal resistance, channel to ambient $(t=10\;s) \eqno(Note\;2a)$ | R _{th (ch-a)} | 65.8 | °C/W |
| Thermal resistance, channel to ambient $(t=10 \; s) \eqno(Note \; 2b)$ | R _{th (ch-a)} | 125 | °C/W |

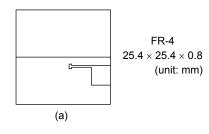
Marking (Note 5)

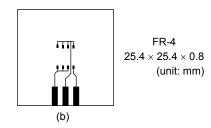


Note 1: The channel temperature should not exceed 150°C during use.

Note 2: (a) Device mounted on a glass-epoxy board (a)

(b) Device mounted on a glass-epoxy board (b)



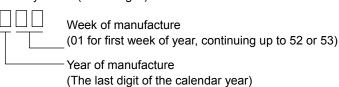


Note 3: V_{DD} = 24 V, T_{ch} = 25°C (initial), L = 0.5 mH, R_G = 25 Ω , I_{AR} = 15 A

Note 4: Repetitive rating: pulse width limited by maximum channel temperature

Note 5: • on the lower left of the marking indicates Pin 1.

* Weekly code: (Three digits)



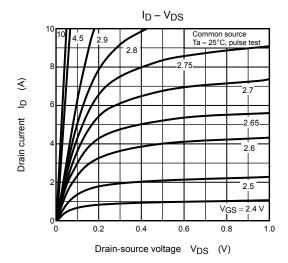
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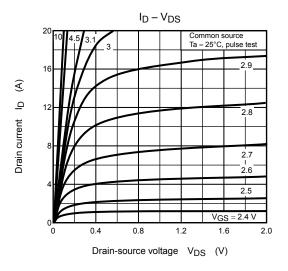
Electrical Characteristics (Ta = 25°C)

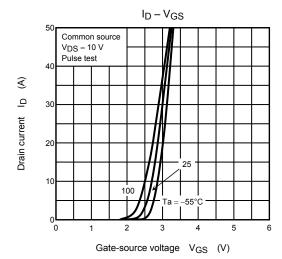
| Characteristic | | Symbol | Test Condition | Min | Тур. | Max | Unit |
|--|----------------|-----------------------|---|---------------------|------|-----|------|
| Gate leakage cur | rent | I _{GSS} | $V_{GS} = \pm 16 \text{ V}, V_{DS} = 0 \text{ V}$ | _ | _ | ±10 | μА |
| Drain cutoff curre | ent | I _{DSS} | V _{DS} = 30 V, V _{GS} = 0 V | _ | _ | 10 | μА |
| Drain-source breakdown voltage | | V (BR) DSS | $I_D = 10$ mA, $V_{GS} = 0$ V | 30 | _ | _ | V |
| Diain-source bre | akdown voltage | V _{(BR) DSX} | $I_D = 10 \text{ mA}, V_{GS} = -20 \text{ V}$ | 15 — — 1.1 — 2.3 | | _ | |
| Gate threshold vo | oltage | V _{th} | V _{DS} = 10 V, I _D = 1 mA | 1.1 | _ | 2.3 | V |
| Drain-source ON-resistance | | Pro (OV) | $V_{GS} = 4.5 \text{ V}, I_D = 7.5 \text{ A}$ | _ | 6.6 | 9.5 | mΩ |
| | | R _{DS} (ON) | V _{GS} = 10 V, I _D = 7.5 A | _ | 5.4 | 6.5 | |
| Forward transfer admittance | | Y _{fs} | V _{DS} = 10 V, I _D = 7.5 A | 12.5 | 25 | _ | S |
| Input capacitance | | C _{iss} | V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz | _ | 2380 | _ | pF |
| Reverse transfer capacitance | | C _{rss} | | _ | 410 | _ | |
| Output capacitance | | Coss | | _ | 980 | _ | |
| Switching time | Rise time | t _r | V _{GS} 10 V I _D = 7.5 A C C C C C C C C C | _ | 9.8 | _ | - ns |
| | Turn-on time | t _{on} | | _ | 21 | _ | |
| | Fall time | t _f | | _ | 15 | _ | |
| | Turn-off time | t _{off} | $V_{DD} \simeq 15 \text{ V}$ Duty $\leq 1\%$, $t_W = 10 \mu\text{s}$ | _ | 60 | _ | |
| Total gate charge (gate-source plus gate-drain) | | Qg | $V_{DD} \simeq 24 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 15 \text{ A}$ | _ | 46 | _ | |
| | | | $V_{DD} \simeq 24 \text{ V}, V_{GS} = 5 \text{ V}, I_D = 15 \text{ A}$ | _ | 26 | _ | |
| Gate-source charge 1 | | Q _{gs1} | | | 7.2 | _ | nC |
| Gate-drain ("Miller") charge | | Q _{gd} | $V_{DD} \simeq 24 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 15 \text{ A}$ | | 12.2 | _ | |
| Gate switch charge | | Q _{SW} | | _ | 15.6 | _ | |

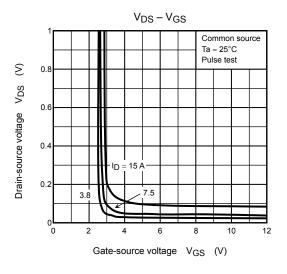
Source-Drain Ratings and Characteristics (Ta = 25°C)

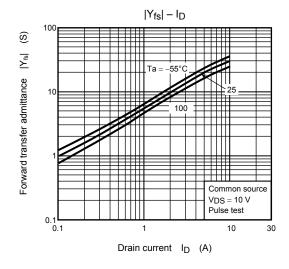
| Character | istic | | Symbol | Test Condition | Min | Тур. | Max | Unit |
|-------------------------|-------|----------|------------------|---|-----|------|------|------|
| Drain reverse current | Pulse | (Note 1) | I _{DRP} | _ | _ | _ | 60 | Α |
| Forward voltage (diode) | | | V_{DSF} | I _{DR} = 15 A, V _{GS} = 0 V | _ | _ | -1.2 | V |

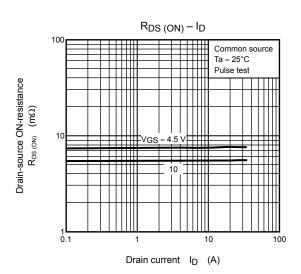


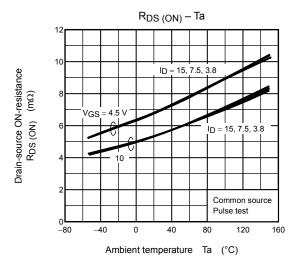


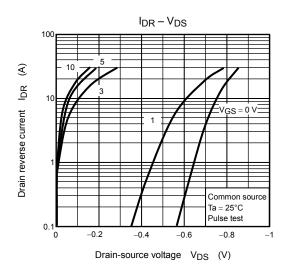


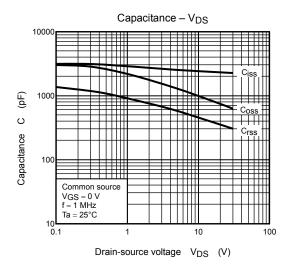


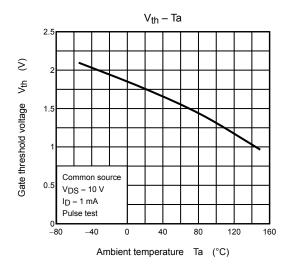


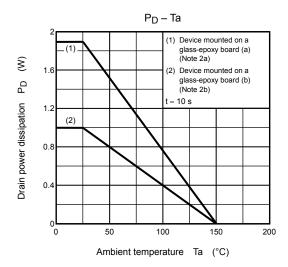


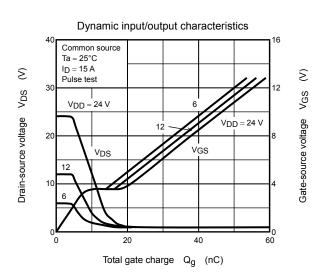




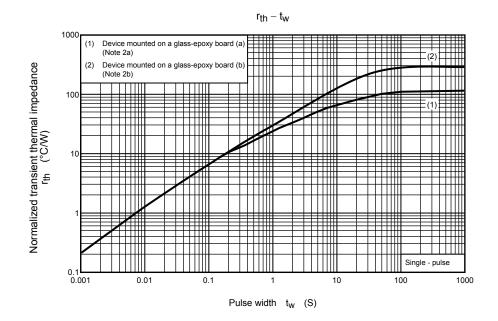


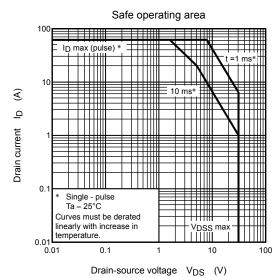






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